

**Search Notes**

Application/Control No.

10/662,287

Examiner

James A. Dudek

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2871

**SEARCHED**

Class	Subclass	Date	Examiner
349	069	3/18/05	D
313	504	3/18/05	D
	506		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
NA		3/18/05	D

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	3/18/05	D